

Docket No.: RYUKA.007

## REQUEST FOR CONTINUED EXAMINATION **UNDER 37 CFR 1.114**

Applicant(s)

Shin-ichi Hashimoto et al.

App. No.

10/672,469

Filed

September 26, 2003

For

ELECTRON BEAM EXPOSURE APPARATUS, DEFLECTION APPARATUS,

AND ELECTRON BEAM EXPOSURE METHOD

Examiner

Anthony G. Quash

Art Unit

2881

## **Commissioner for Patents** Alexandria, VA 22313-1450

This is a request for continued examination under 37 CFR 1.114 in the above-identified utility patent application.

## Enclosed:

- An amendment in twelve (12) pages in response to the office action dated October 5, 2004 which (X) is a bonna fide attempt to advance the application.
- (X) A check in the amount of \$878.00 for RCE fee and one (1) excess independent claim fee (cause by the amendment in the claims concurrently submitted herewith) is enclosed.
- (X) Return prepaid postcard.

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

November 22, 2004 (Date)

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